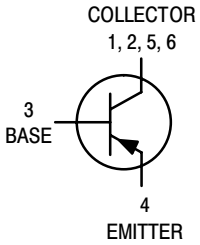
MBT35200MT1

High Current Surface Mount PNP Silicon Switching Transistor for Load Management in Portable Applications

ON Semiconductor®

http://onsemi.com

35 VOLTS
2.0 AMPS
PNP TRANSISTOR



MAXIMUM RATINGS (T_A = 25°C)

Rating	Symbol	Max	Unit
Collector-Emitter Voltage	V_{CEO}	−35	Vdc
Collector-Base Voltage	V_{CBO}	−55	Vdc
Emitter-Base Voltage	V_{EBO}	−5.0	Vdc
Collector Current − Continuous	I_C	−2.0	Adc
Collector Current − Peak	I_{CM}	−5.0	A
Electrostatic Discharge	ESD	HBM Class 3 MM Class C	

THERMAL CHARACTERISTICS

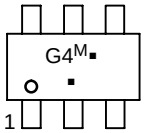
Characteristic	Symbol	Max	Unit
Total Device Dissipation T_A = 25°C Derate above 25°C	P_D (Note 1)	625 5.0	mW mW/°C
Thermal Resistance, Junction−to−Ambient	$R_{\theta JA}$ (Note 1)	200	°C/W
Total Device Dissipation T_A = 25°C Derate above 25°C	P_D (Note 2)	1.0 8.0	W mW/°C
Thermal Resistance, Junction−to−Ambient	$R_{\theta JA}$ (Note 2)	120	°C/W
Thermal Resistance, Junction−to−Lead #1	$R_{\theta JL}$	80	°C/W
Total Device Dissipation (Single Pulse < 10 sec.)	$P_{Dsingle}$ (Notes 2 & 3)	1.75	W
Junction and Storage Temperature Range	T_J, T_{stg}	−55 to +150	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

1. FR−4 @ Minimum Pad
2. FR−4 @ 1.0 X 1.0 inch Pad
3. ref: Figure 9

MARKING DIAGRAM

CASE 318G
TSOP−6
STYLE 6



M = Date Code
▪ = Pb−Free Package
(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping†
MBT35200MT1	TSOP−6	3000/Tape & Reel
MBT35200MT1G	TSOP−6 (Pb−Free)	3000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Typical	Max	Unit
OFF CHARACTERISTICS					
Collector−Emitter Breakdown Voltage (I_C = −10 mAdc, I_B = 0)	$V_{(BR)CEO}$	−35	−45	−	Vdc
Collector−Base Breakdown Voltage (I_C = −0.1 mAdc, I_E = 0)	$V_{(BR)CBO}$	−55	−65	−	Vdc
Emitter−Base Breakdown Voltage (I_E = −0.1 mAdc, I_C = 0)	$V_{(BR)EBO}$	−5.0	−7.0	−	Vdc
Collector Cutoff Current (V_{CB} = −35 Vdc, I_E = 0)	I_{CBO}	−	−0.03	−0.1	μAdc
Collector−Emitter Cutoff Current (V_{CES} = −35 Vdc)	I_{CES}	−	−0.03	−0.1	μAdc
Emitter Cutoff Current (V_{EB} = −4.0 Vdc)	I_{EBO}	−	−0.01	−0.1	μAdc
ON CHARACTERISTICS					
DC Current Gain (1) (I_C = −1.0 A, V_{CE} = −1.5 V) (I_C = −1.5 A, V_{CE} = −1.5 V) (I_C = −2.0 A, V_{CE} = −3.0 V)	h_{FE}	 100 100 100	 200 200 200	 − 400 −	
Collector−Emitter Saturation Voltage (Note 1.) (I_C = −0.8 A, I_B = −0.008 A) (I_C = −1.2 A, I_B = −0.012 A) (I_C = −2.0 A, I_B = −0.02 A)	$V_{CE(sat)}$	 − − −	 −0.125 −0.175 −0.260	 −0.15 −0.20 −0.31	V
Base−Emitter Saturation Voltage (Note 1.) (I_C = −1.2 A, I_B = −0.012 A)	$V_{BE(sat)}$	−	−0.68	−0.85	V
Base−Emitter Turn−on Voltage (Note 1.) (I_C = −2.0 A, V_{CE} = −3.0 V)	$V_{BE(on)}$	−	−0.81	−0.875	V
Cutoff Frequency (I_C = −100 mA, V_{CE} = −5.0 V, f = 100 MHz)	f_T	100	−	−	MHz
Input Capacitance (V_{EB} = −0.5 V, f = 1.0 MHz)	Cibo	−	600	650	pF
Output Capacitance (V_{CB} = −3.0 V, f = 1.0 MHz)	Cobo	−	85	100	pF
Turn−on Time (V_{CC} = −10 V, I_{B1} = −100 mA, I_C = −1 A, R_L = 3 Ω)	t_{on}	−	35	−	nS
Turn−off Time (V_{CC} = −10 V, I_{B1} = I_{B2} = −100 mA, I_C = 1 A, R_L = 3 Ω)	t_{off}	−	225	−	nS

1. Pulsed Condition: Pulse Width = 300 μsec, Duty Cycle ≤ 2%

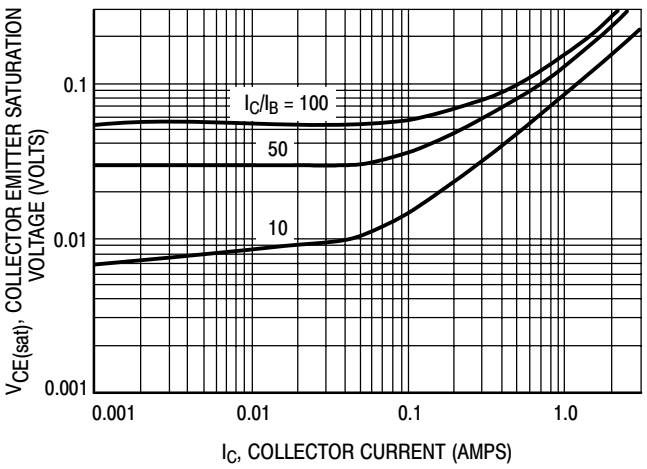


Figure 1. Collector Emitter Saturation Voltage versus Collector Current

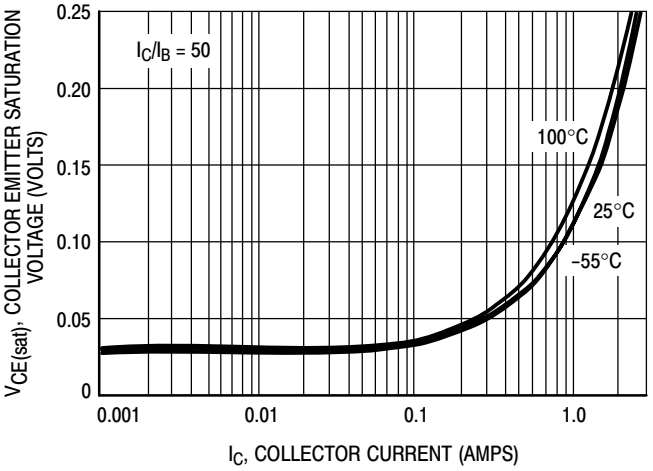


Figure 2. Collector Emitter Saturation Voltage versus Collector Current

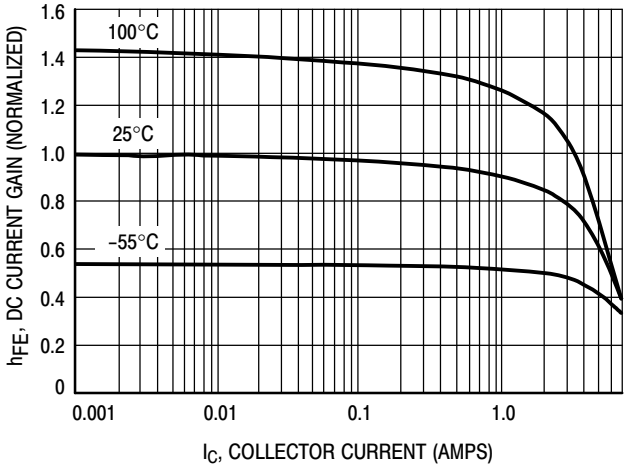


Figure 3. DC Current Gain versus Collector Current

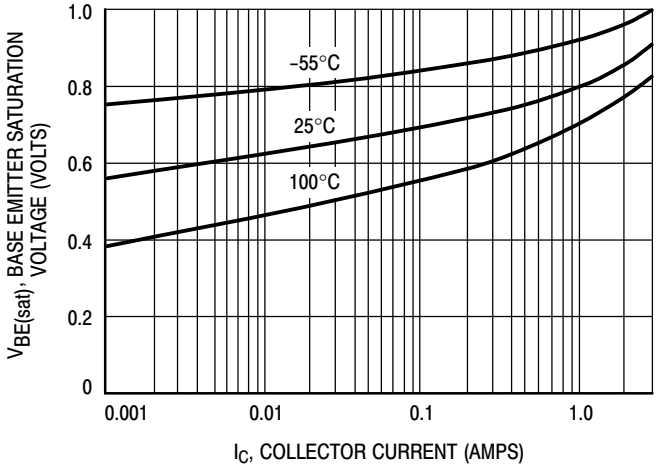


Figure 4. Base Emitter Saturation Voltage versus Collector Current

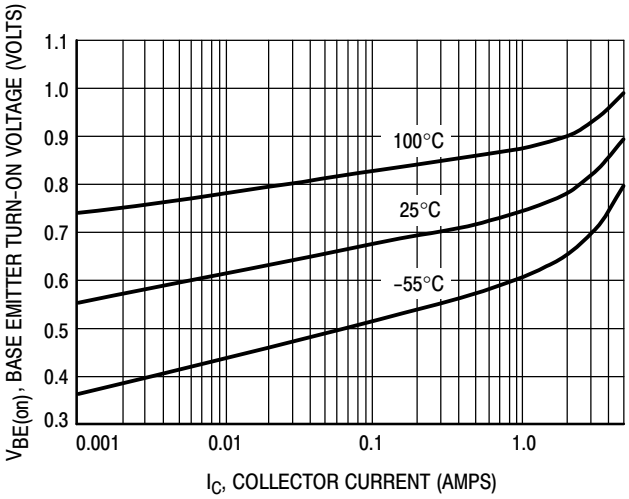


Figure 5. Base Emitter Turn−On Voltage versus Collector Current

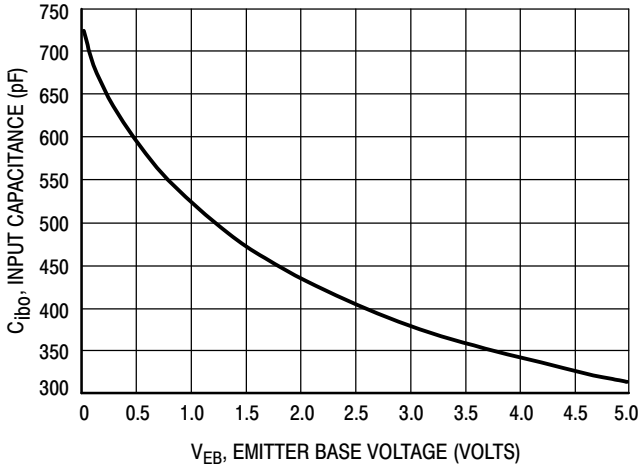


Figure 6. Input Capacitance

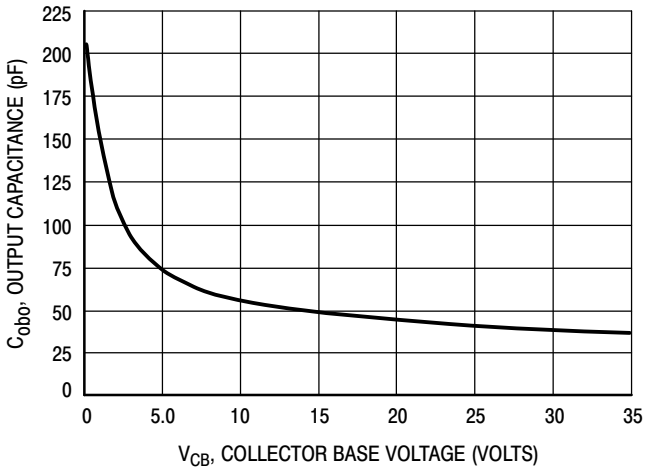


Figure 7. Output Capacitance

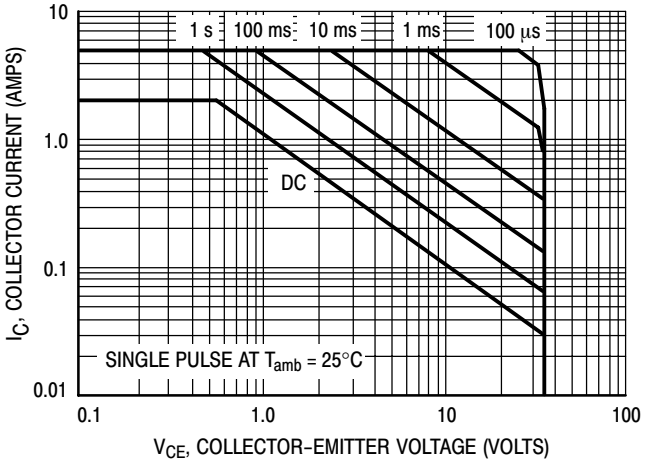


Figure 8. Safe Operating Area

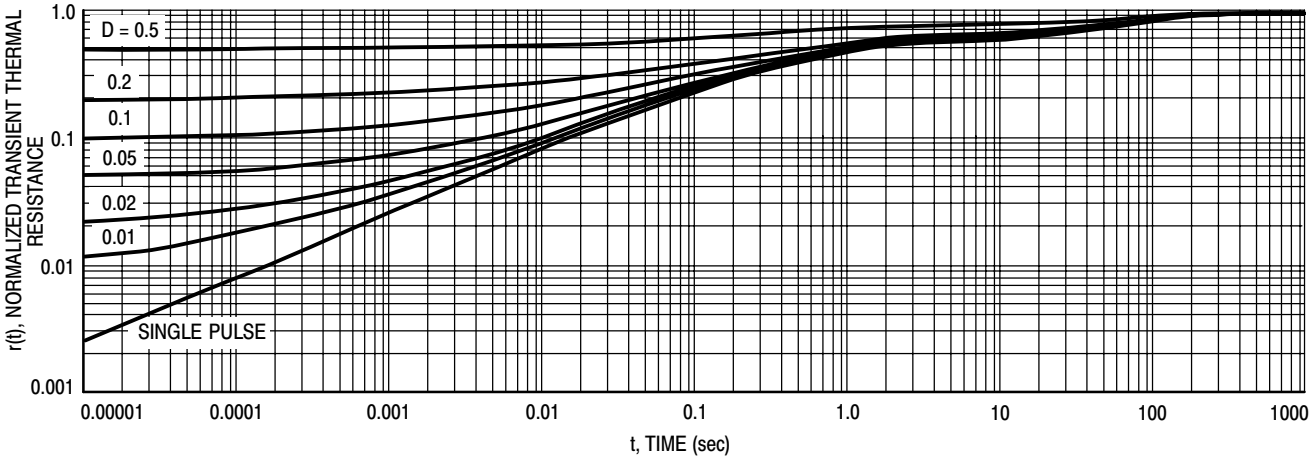
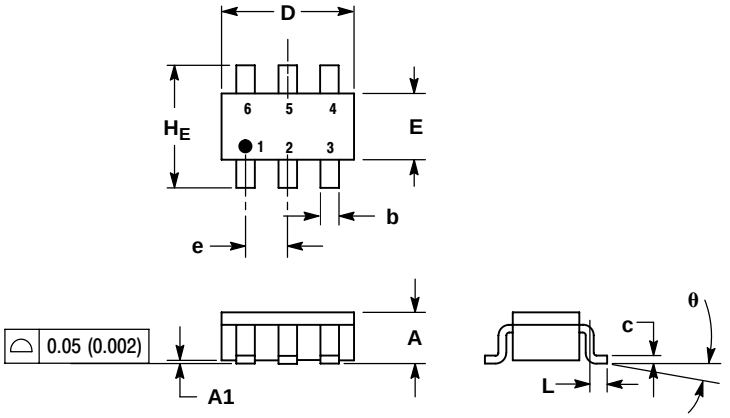


Figure 9. Normalized Thermal Response

PACKAGE DIMENSIONS

TSOP−6
CASE 318G−02
ISSUE P

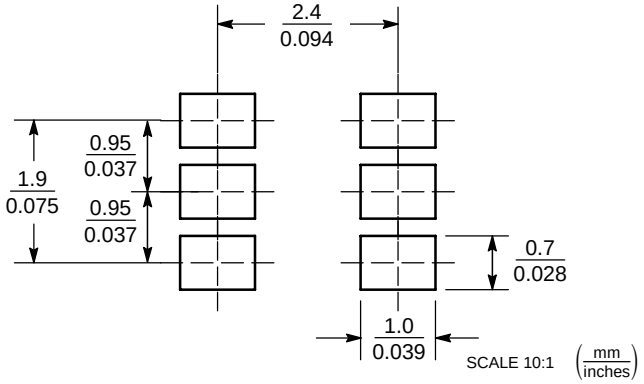


NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.
4. DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
A	0.90	1.00	1.10	0.035	0.039	0.043
A1	0.01	0.06	0.10	0.001	0.002	0.004
b	0.25	0.38	0.50	0.010	0.014	0.020
c	0.10	0.18	0.26	0.004	0.007	0.010
D	2.90	3.00	3.10	0.114	0.118	0.122
E	1.30	1.50	1.70	0.051	0.059	0.067
e	0.85	0.95	1.05	0.034	0.037	0.041
L	0.20	0.40	0.60	0.008	0.016	0.024
H_E	2.50	2.75	3.00	0.099	0.108	0.118
θ	0°	–	10°	0°	–	10°

STYLE 6:
PIN 1. COLLECTOR
2. COLLECTOR
3. BASE
4. EMITTER
5. COLLECTOR
6. COLLECTOR

SOLDERING FOOTPRINT*



*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PUBLICATION ORDERING INFORMATION

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